IN THE CLAIMS:

- 1. (Cancelled)
- 2. (Cancelled)
- 3. (Previously Presented) The method of claim 14, wherein the hydroxylamine derivative is present in a total amount from about 1% to about 20% by weight of the composition.
- 4. (Previously Presented) The method of claim 14, wherein the corrosion inhibitor comprises benzotriazole.
- 5. (Previously Presented) The method of claim 4, wherein the corrosion inhibitor consists essentially of benzotriazole.
- 6. (Cancelled)
- 7. (Previously Presented) The method of claim 14, wherein the water is present in a total amount from about 90% to about 99% by weight of the composition.
- 8. (Currently Amended) The method of claim 14, wherein the composition comprises a sufficient amount of the acid and/or [[a]] the base to adjust the pH of the composition to a desired level between pH 2 and pH 12.
- 9. (Currently Amended) The method of claim 8, wherein the acid and/or the base are present in a total amount from about 0.01% to about 2% by weight of the composition.
- 10. (Currently Amended) The method of claim 14, wherein the composition further comprises one or more of the following: <u>a two carbon atom linkage alkanolamine compound</u>, a quaternary ammonium salt, a chelating agent, an organic solvent, a non-hydroxyl-containing amine compound, a surfactant, an additional oxidizing agent, and a non-abrasive additive.

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- 11. (Cancelled)
- 12. (Cancelled)
- 13. (Cancelled)

14. (Currently Amended) A method for chemical mechanical polishing of a substrate comprising:

providing a substantially abrasive-free chemical mechanical polishing composition, wherein the composition comprises

containing less than 1.0 % by weight abrasive,
that comprises hydroxylamine or a hydroxylamine derivative,
a corrosion inhibitor,
water, and

optionally a sufficient amount of an acid and/or a base to adjust the pH of the composition to a desired level, wherein the majority of the composition comprises water;

contacting the chemical mechanical polishing composition with a substrate having a metal oxide layer surface, upon which metal oxide surface a barrier layer is disposed, upon which barrier layer metal oxide layer surface a metal layer is disposed, and chemically mechanically polishing the substrate by contacting the substrate surface containing the polishing composition with an abrasive a polishing pad at an applied pressure of not more than about 2 psi and by moving the pad in relation to the substrate [[,]].

the removal rate of the barrier layer is greater than about 500 Å/min, the removal rate of the metal oxide layer is less than about 10 Å/min, the removal rate of the metal layer is less than about 250 Å/min.[[,]] the hydroxylamine derivative is substantially free of hydroxylamine, and the composition further comprises a two carbon atom linkage alkanolamine compound.

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15. (Cancelled)

wherein:

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16. (Currently Amended) The method of claim 14, wherein the removal rate of the metal layer during the chemical mechanical polishing step is removed at a rate of greater than about 10 Å/min.

17. (Cancelled)

- 18. (Currently Amended) The method of claim 14, wherein the <u>substantially</u> abrasive-free chemical mechanical polishing composition is substantially free of one or more of the following: acid and/or base to adjust pH, <u>two carbon atom linkage alkanolamine compounds</u>, quaternary ammonium salts, chelating agents, organic solvents, non-hydroxyl-containing amine compounds, surfactants, additional oxidizing agents, and non-abrasive additives.
- 19. (Currently Amended) The method of claim 14, wherein the <u>substantially</u> abrasive-free chemical mechanical polishing composition consists essentially of:

about 1% to about 5% by weight of a hydroxylamine derivative selected from the group consisting of hydroxylamine nitrate, hydroxylamine sulfate, <u>hydroxylamine chloride</u> and mixtures thereof;

about 0.01% to about 0.05% by weight of benzotriazole;

about 90% to 99% by weight of water; and

less than about 2% by weight of the acid and/or [[a]] the base to adjust the pH of the composition to a desired level... and

a two carbon atom-linkage alkanolamine compound.

20. (Cancelled)

- 21. (Previously Presented) The method of claim 14, wherein the metal layer of the substrate comprises copper.
- 22. (Cancelled)
- 23. (Cancelled)

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- 24. (Previously Presented) The method of claim 14, wherein the pH of the composition is between about 4 and about 10.
- 25. (Previously Presented) The method of claim 14, wherein the pH of the composition is between about 5.2 and about 5.5.
- 26. (Currently Amended) The method of claim 14, wherein the <u>hydroxylamine or</u> hydroxylamine derivative is present in a total amount from about 0.2% to about 20% by weight of the composition and wherein the concentration of the acid and/or a base to adjust the pH of the composition is from about 0.01 to about 1%.

27. (Cancelled)

- 28. (Previously Presented) The method of claim 14, wherein the hydroxylamine derivative comprises hydroxylamine nitrate.
- 29. (Previously Presented) The method of claim 14, wherein the hydroxylamine derivative comprises hydroxylamine sulfate.
- 30. (Previously Presented) The method of claim 14, wherein the hydroxylamine derivative comprises hydroxylamine sulfate and hydroxylamine nitrate.
- 31. (Cancelled)
- 32. (Cancelled)
- 33. (Cancelled)